Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/827,267	FURUKAWA ET AL,	
Examiner	Art Unit	
Dmitry Levitan	2616	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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